#### **Innovation for Our Energy Future**

# Results from the Second International Module Inter-comparison

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### **History**

1987 to 1989 - PEP '87

Cells, cell in module package and module of identical type 2 day meeting of participants, PTB issued formal report, 1990 presented at 21 IEEE PVSC

Range Si Modules;  $I_{sc}$  = 2-5%, FF = 1-2%,  $V_{oc}$  = 2-5% Range a-Si tandem Modules  $I_{sc}$  = 8%, FF= 2.5%,  $V_{oc}$  = 1% Final Report analyzed data using 2 standard deviations,  $I_{sc}$  2-6% for Si, 3-10% for a-Si, FF 1-2%,  $V_{oc}$  0-5%

1992 to 1994 - ASTM E1036 Interlaboratory Test Program encapsulated cells provided, (Range in  $P_{max} \sim 5\%$ )  $P_{max} = 95\% \text{ repeatability limit (within laboratory)} = 0.7\%$   $P_{max} = 95\% \text{ reproducibility limit (between laboratory)} = 6.7\%$ 

Manufacture sponsored intercomparisons - often only 2 labs & results usually not published.



#### Goals

Evaluate differences in module IV parameters With Respect to Standard Reference Conditions between National Calibration facilities

ISO-17025 Accredited PV

**Qualification or Calibration Labs** 

Modules Chosen to –

Identify differences in participants scope

Flat-plate, Concentrator

Single-junction, Multi-junction

Crystalline Si, Thin-film

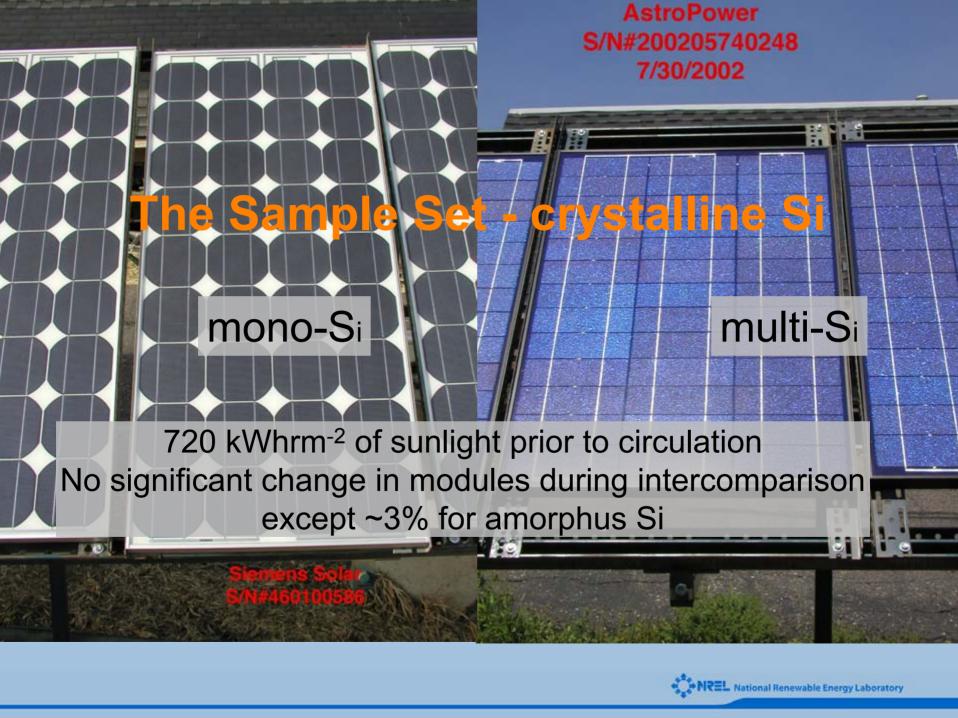
"Typical" Quantum Efficiency supplied by the manufacturer

No reference cell is provided

Include Samples that have had measurement related problems

Bias Rate, Current Matching for Multi-junction,

Sensitivity to Spatial Nonuniformity, Tracking for concentrator



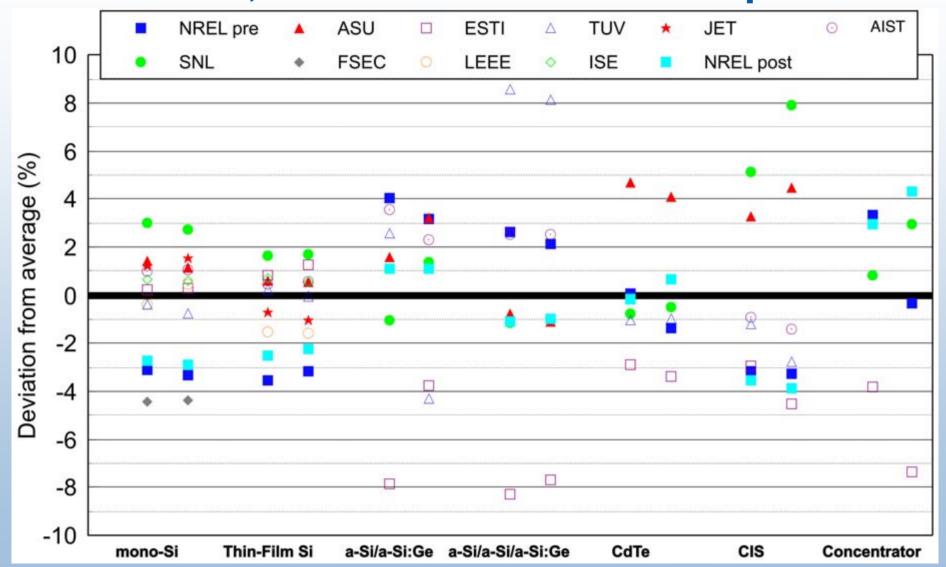
## The Sample Set - CdTe & CIGS



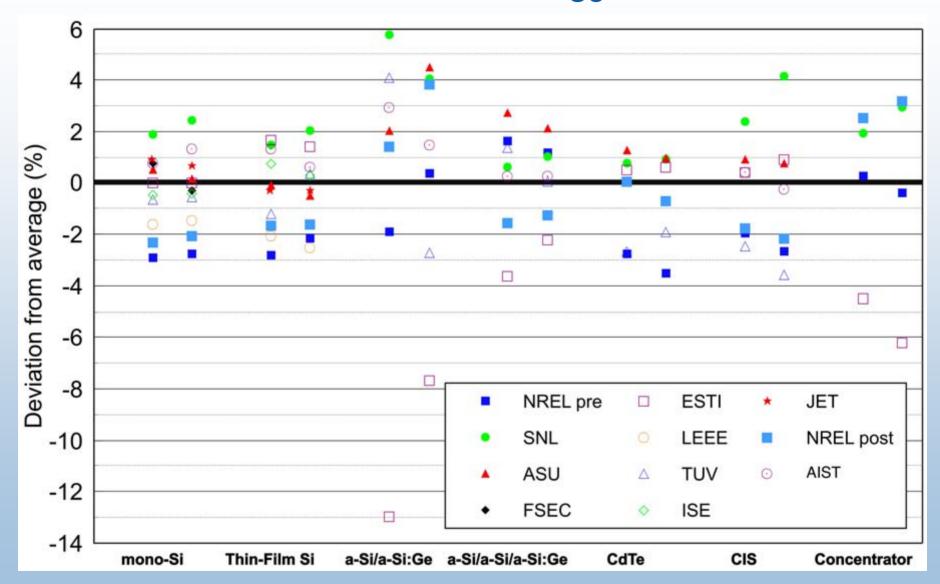




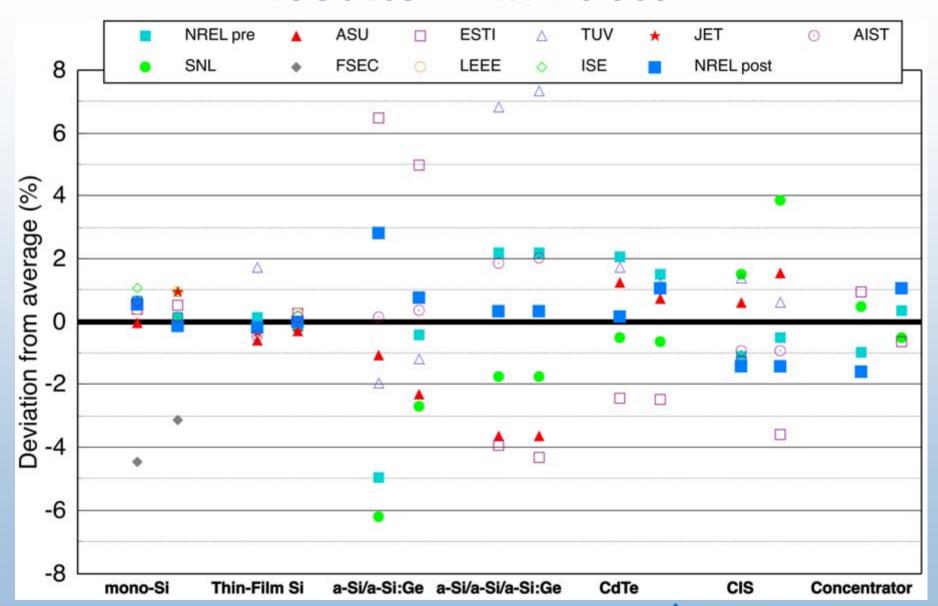
# Results - P<sub>max</sub> @ 25 C, 1000 Wm<sup>-2</sup>, IEC Global Reference spectrum



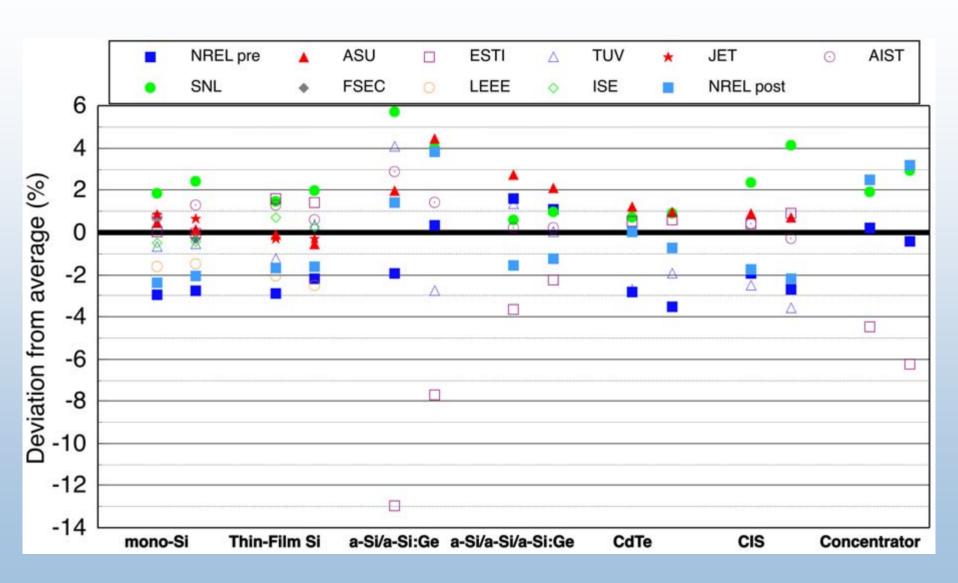
# Results - I<sub>sc</sub>



#### **Results - Fill Factor**



#### Results - Voc



### **Summary**

- Range in I<sub>sc</sub> for Si 5%, CIS 5 & 8%, CdTe 4%,
   Multijunction range 4 to 19% depending on module.
   Not having the luxury of a matched reference cell,
   Representative cell, or the Measured Module spectral responsivity may be the cause of larger differences than previous module intercomparisons.
- Range in P<sub>max</sub> for Si 6 & 7%, CIS or CdTe 8%,
  Multijunction range 7 to 17% depending on module.
- Range in V<sub>oc</sub> for Si 4 to 5%. About an 8 C temperature range would be required to account for a 5% V<sub>oc</sub> difference.
- Several participants didn't measure concentrator or thinfilm modules because they were outside their scope.

